United States Patent [19]

Suwa et al.

[11] **Des. 263,809**

[45] ** **Apr. 13, 1982**

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[54] **MICROMETER**

[75] Inventors: **Hiroaki Suwa; Kiyohiro Nakata,** both of Hiromachi, Japan

[73] Assignee: **Mitutoyo Mfg. Co., Ltd.,** Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **83,626**

[22] Filed: **Oct. 11, 1979**

[51] **Int. Cl.** .... **D10—04**
[52] **U.S. Cl.** **D10/73**
[58] **Field of Search** D10/73; 33/166

[56] **References Cited**

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D. 239,704	4/1976	Morgan	D10/73
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Alina Catalog No. IN-200-2 Instrument Div., p. 7-Diac Micrometer at center.

Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—Koda and Androlia

[57] **CLAIM**

The ornamental design for a micrometer, substantially as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a micrometer showing our new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a top plan view thereof;
FIG. **4** is a rear elevational view thereof;
FIG. **5** is a left-side elevational view thereof;
FIG. **6** is a right-side elevational view thereof; and
FIG. **7** is a bottom plan view thereof.

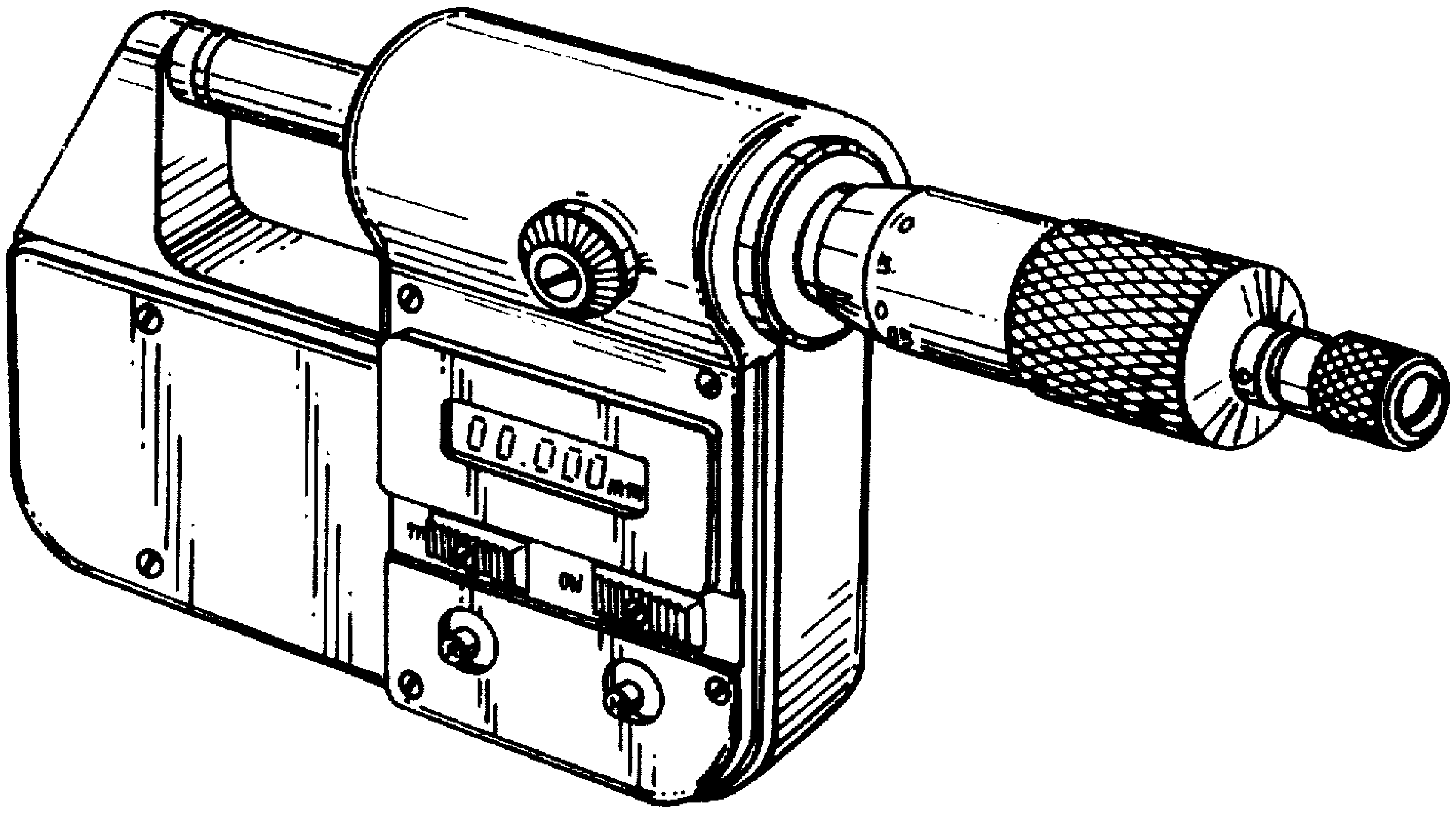

FIG. 1

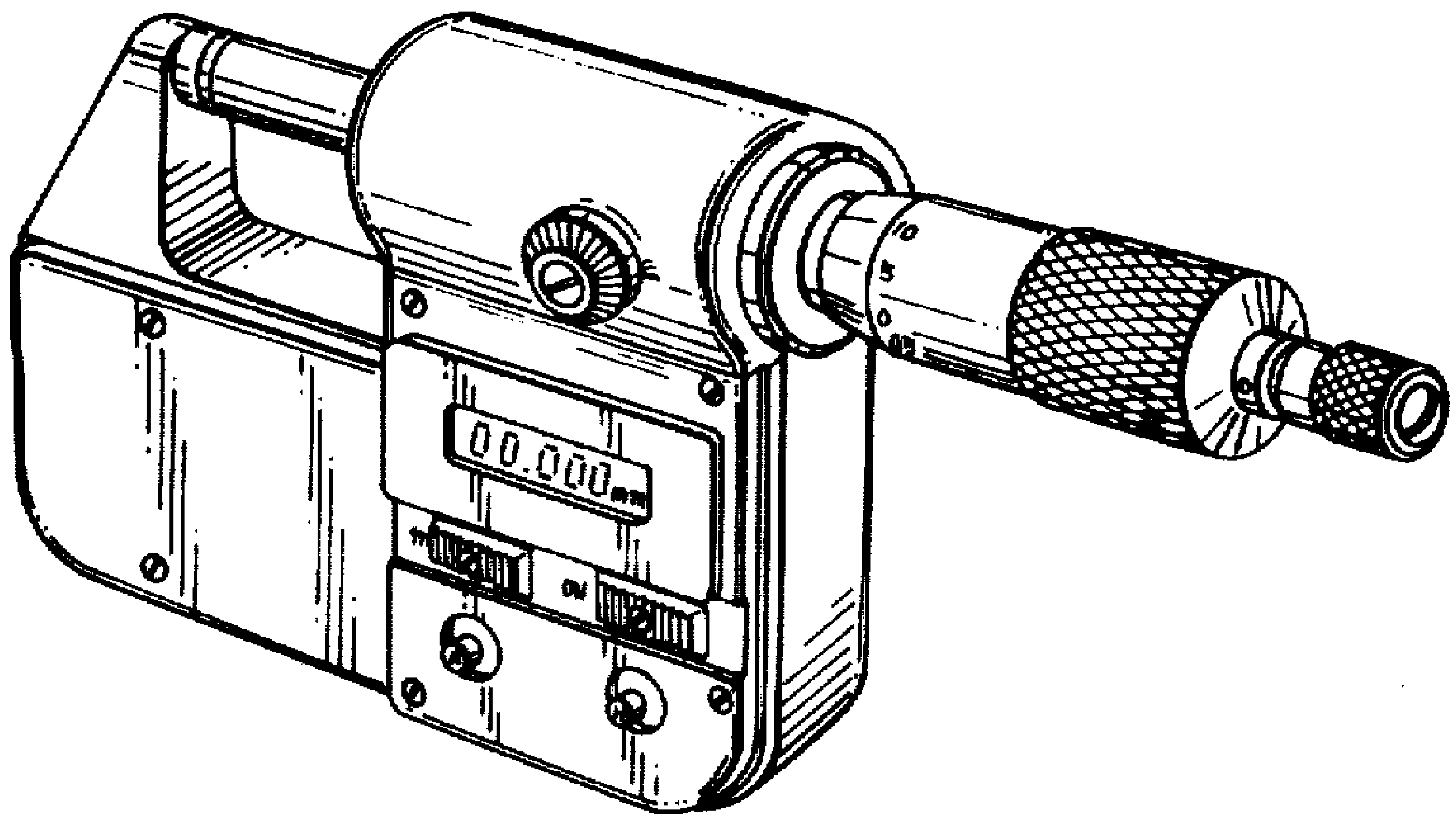

FIG. 2

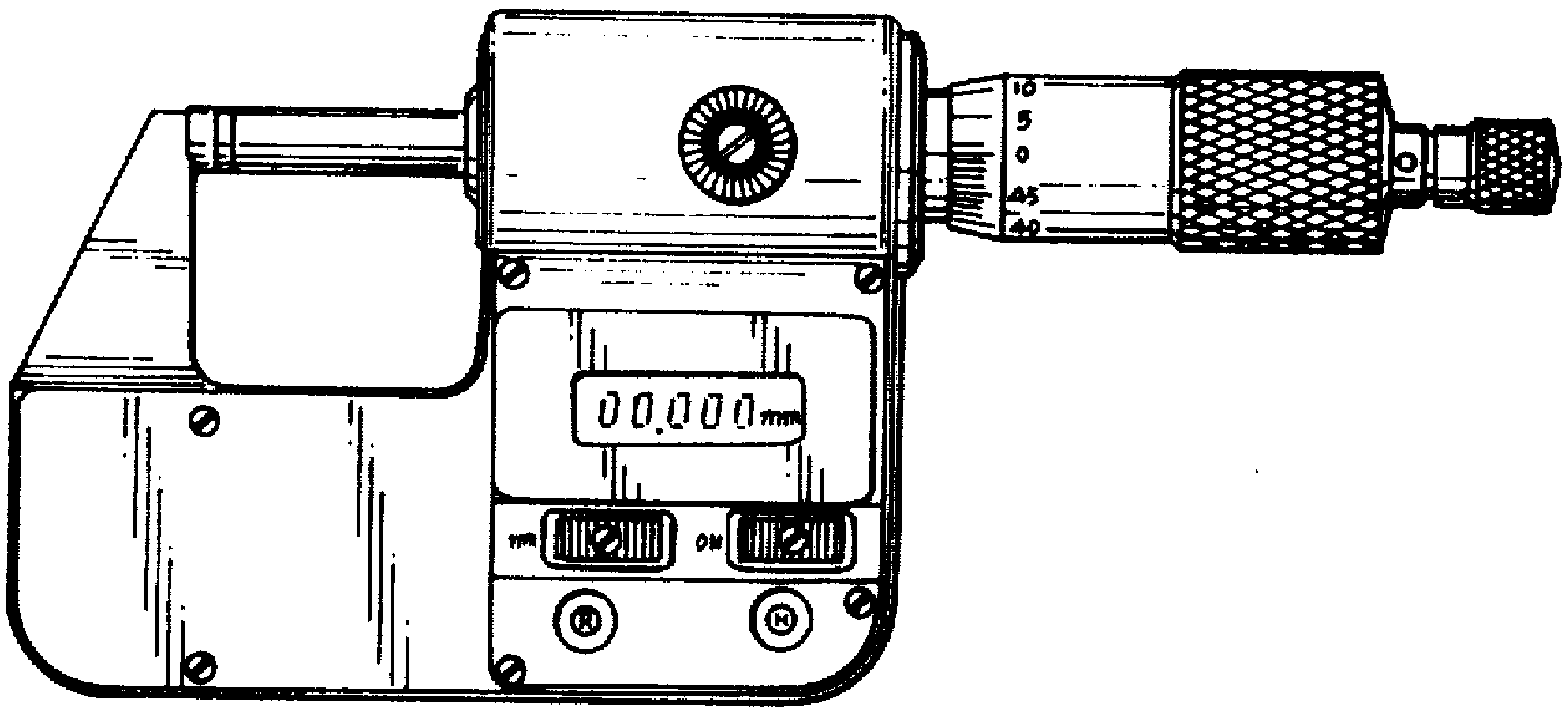

FIG. 3

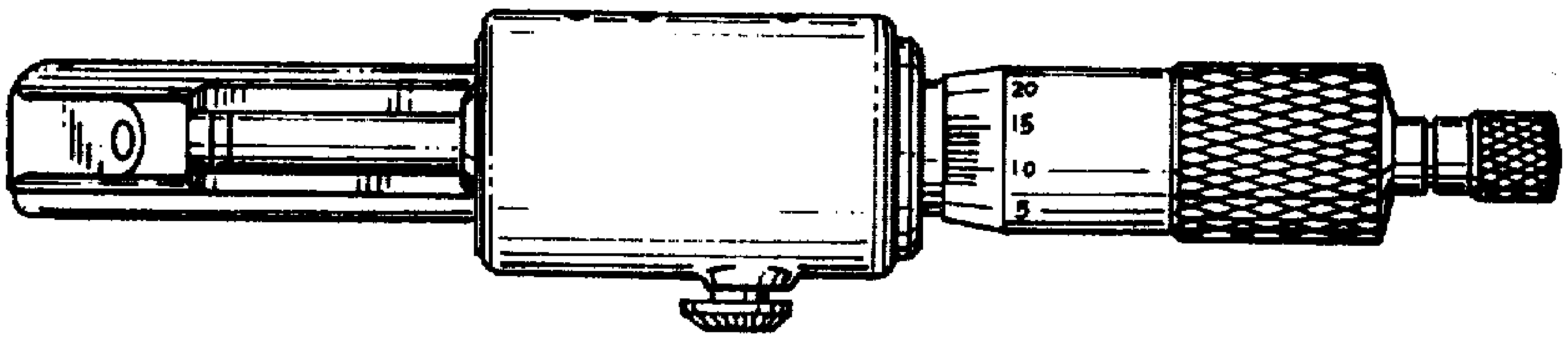

FIG.4

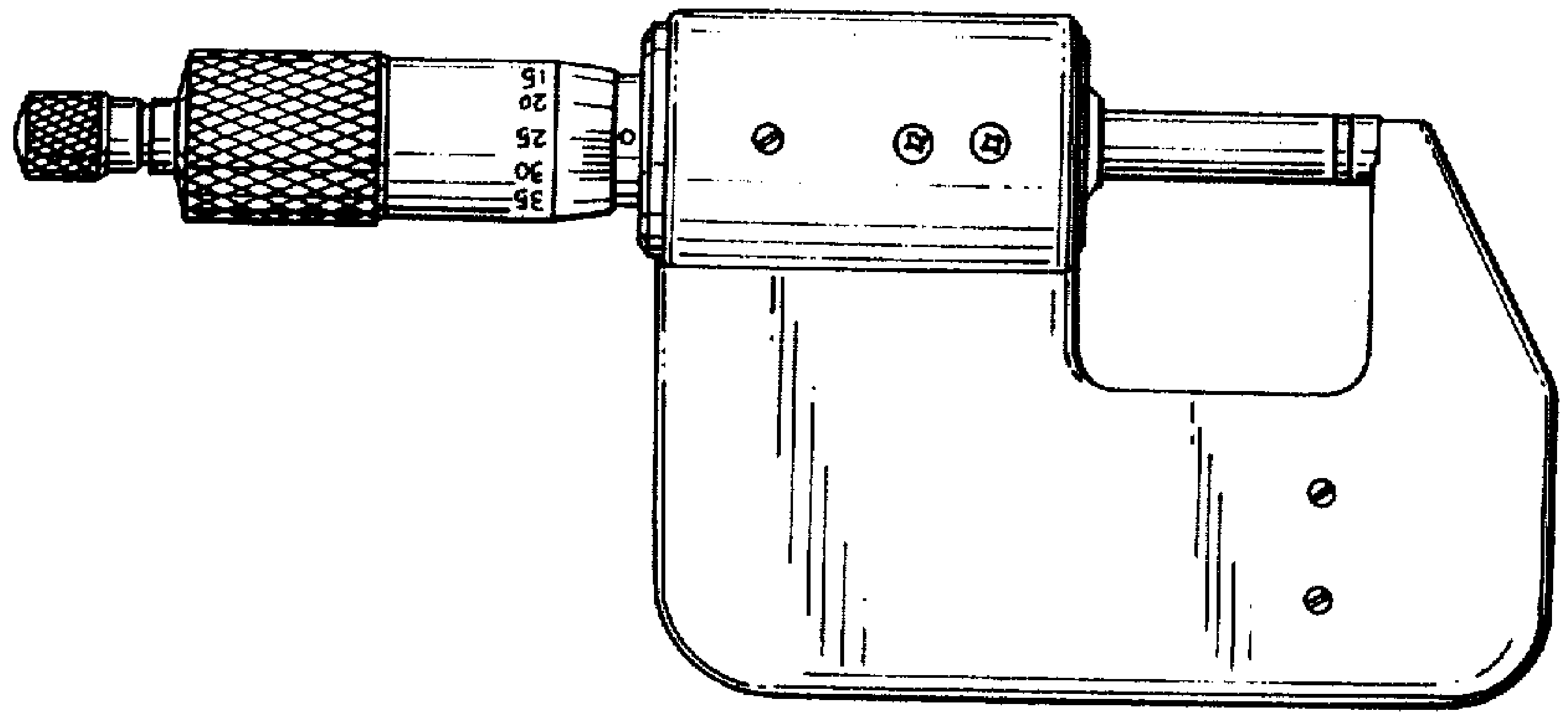

FIG.5

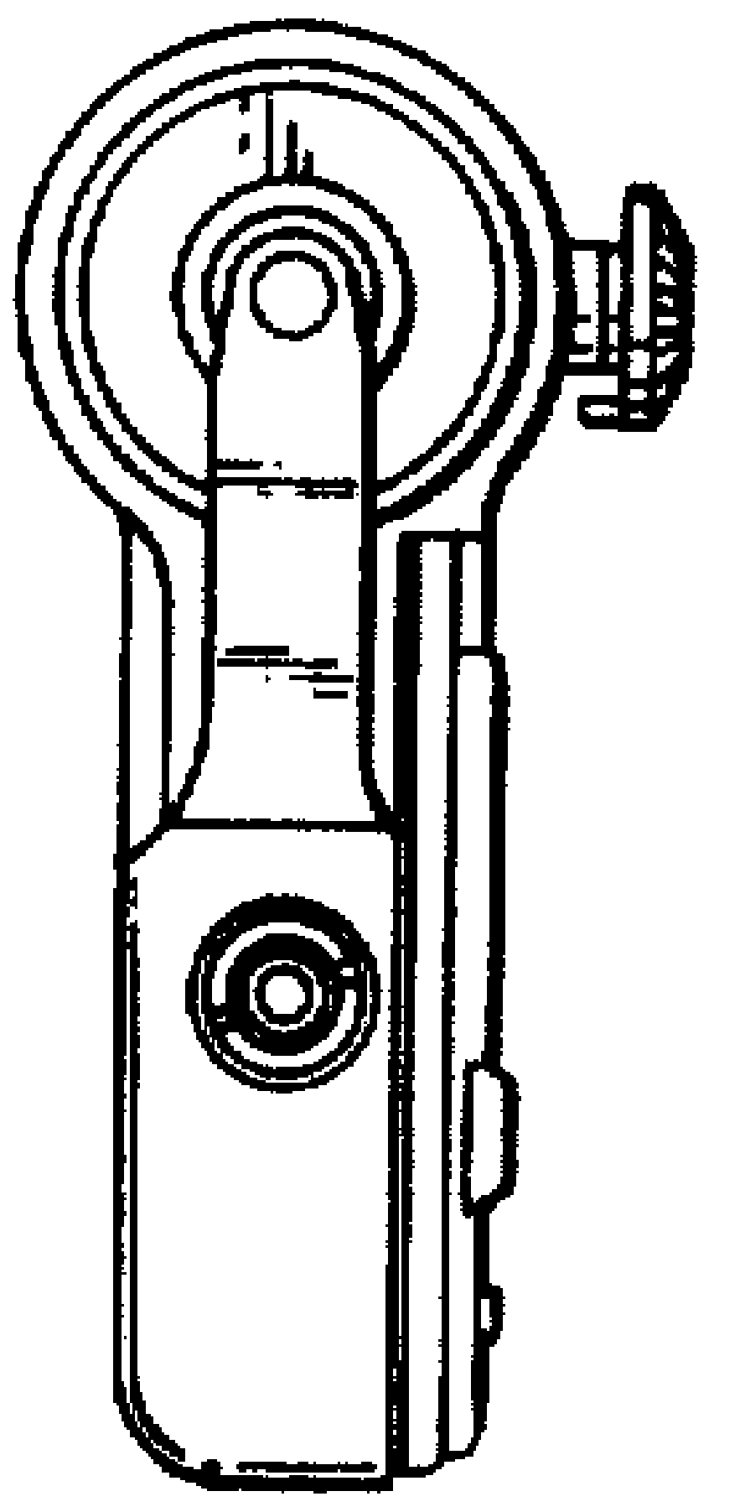

FIG.6

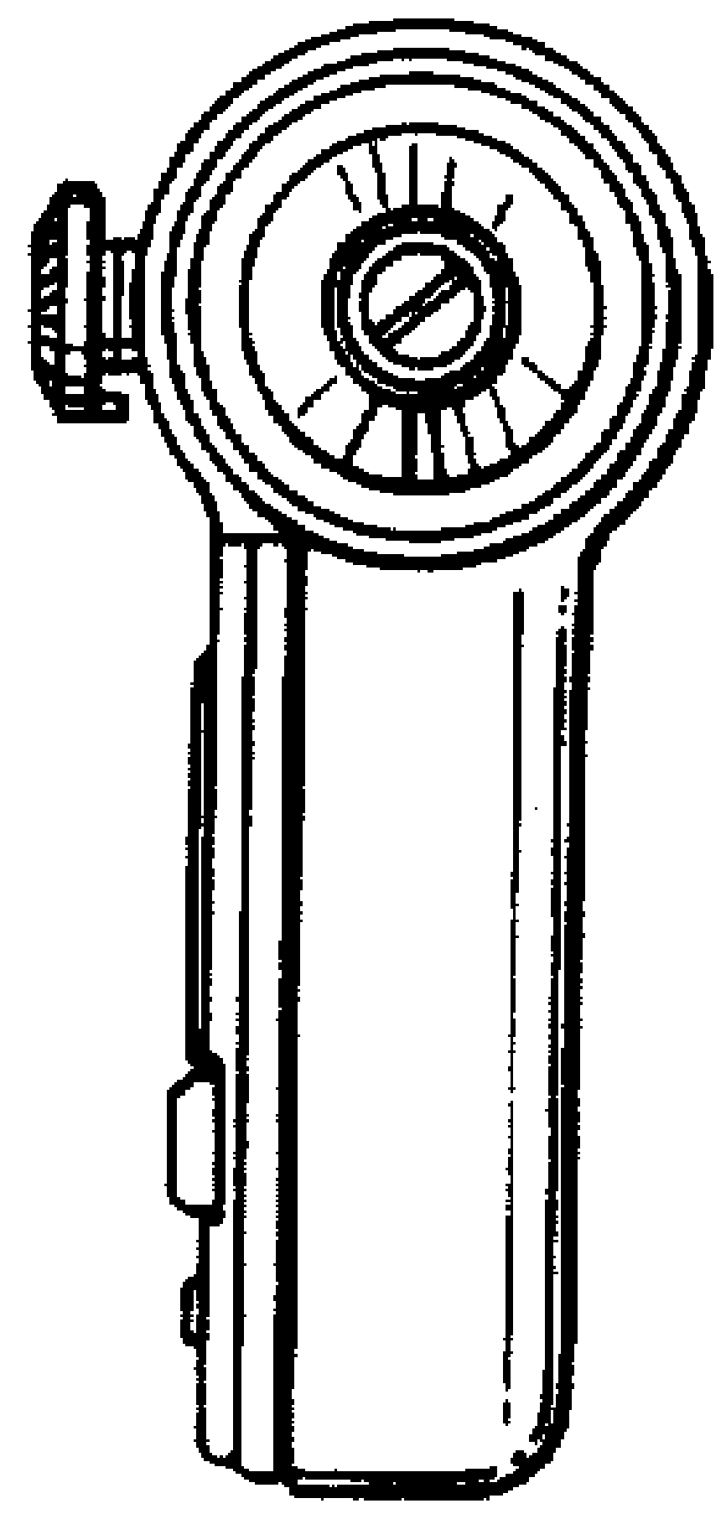

FIG.7